

Search Notes

Application/Control No.

10/808,425

Examiner

Sin J. Lee

Applicant(s)/Patent under
Reexamination

IWASHITA ET AL.

Art Unit

1752

SEARCHED

Class	Subclass	Date	Examiner
430	270.1	4-15	SJL
↓	325	↓ -05	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR